

<b>Notice of References Cited</b>	Application/Control No. 10/676,144	Applicant(s)/Patent Under Reexamination YEOM ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,563,824	01-1986	Baun, Kenneth W.	33/568
	B	US-5,481,423	01-1996	Aoki, Yoshitaka	360/99.06
	C	US-4,456,935	06-1984	Janosi, Marcell	360/99.04
	D	US-5,120,292	06-1992	Ueda et al.	493/124
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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